United States Patent [19]

Sato

[11] **Patent Number: Des. 311,411**

[45] **Date of Patent: ** Oct. 16, 1990**

[54] **INSTRUMENT FOR DIAGONAL OBSERVATION BY MICROSCOPE**

[76] Inventor: **Zensuke Sato,** 2607-5 Oaza-kainuma, Kawagoe-shi, Saitama-ken, Japan

[**] Term: **14 Years**

[21] Appl. No.: **187,416**

[22] Filed: **Apr. 28, 1988**

[30] **Foreign Application Priority Data**

Dec. 15, 1987 [JP] Japan 62-50955

[52] **U.S. Cl.** **D16/131;** D16/130

[58] **Field of Search** D16/131, 130, 136, 134; 350/520, 511, 618, 519, 521-523, 414, 419

[56] **References Cited**

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Attorney, Agent, or Firm—Flynn, Thiel, Boutell & Tanis

[57] **CLAIM**

The ornamental design of an instrument for diagonal observation by microscope, as shown and described.

DESCRIPTION

FIG. **1** is a front elevational view of an instrument for diagonal observation by microscope showing my new design;

FIG. **2** is a rear elevational view thereof;

FIG. **3** is a top plan view thereof;

FIG. **4** is a bottom plan view thereof;

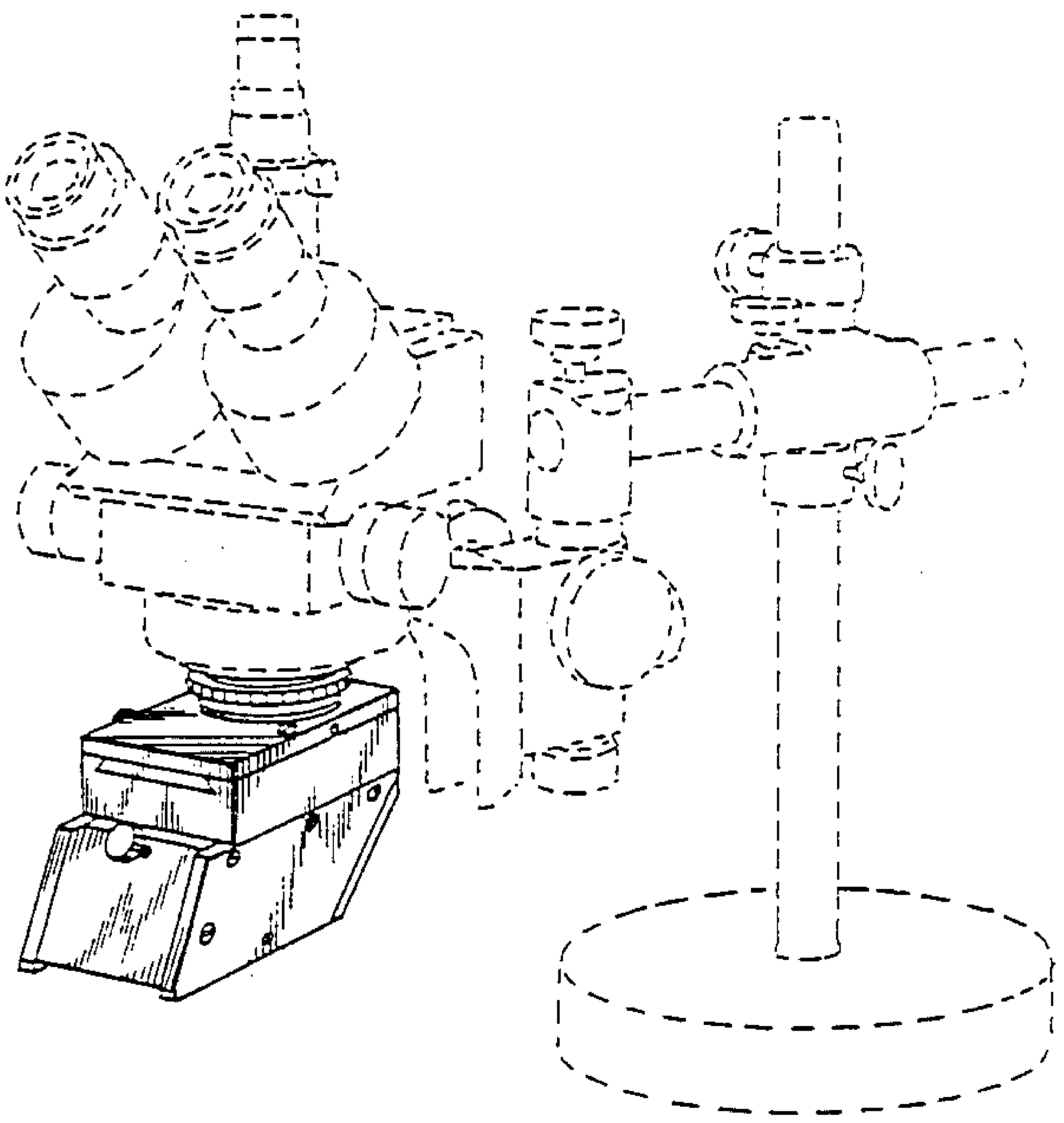
FIG. **5** is a left side elevational view thereof;

FIG. **6** is a right side elevational view thereof;

FIG. **7** is a sectional view taken along line VII—VII in FIG. **1;**

FIG. **8** is a perspective view which illustrates the instrument mounted in association with a microscope, the latter being shown by broken lines for illustrative purposes only and forming no part of the claimed design; and

FIG. **9** is a right side elevational view similar to FIG. **6** illustrating a different operational state.



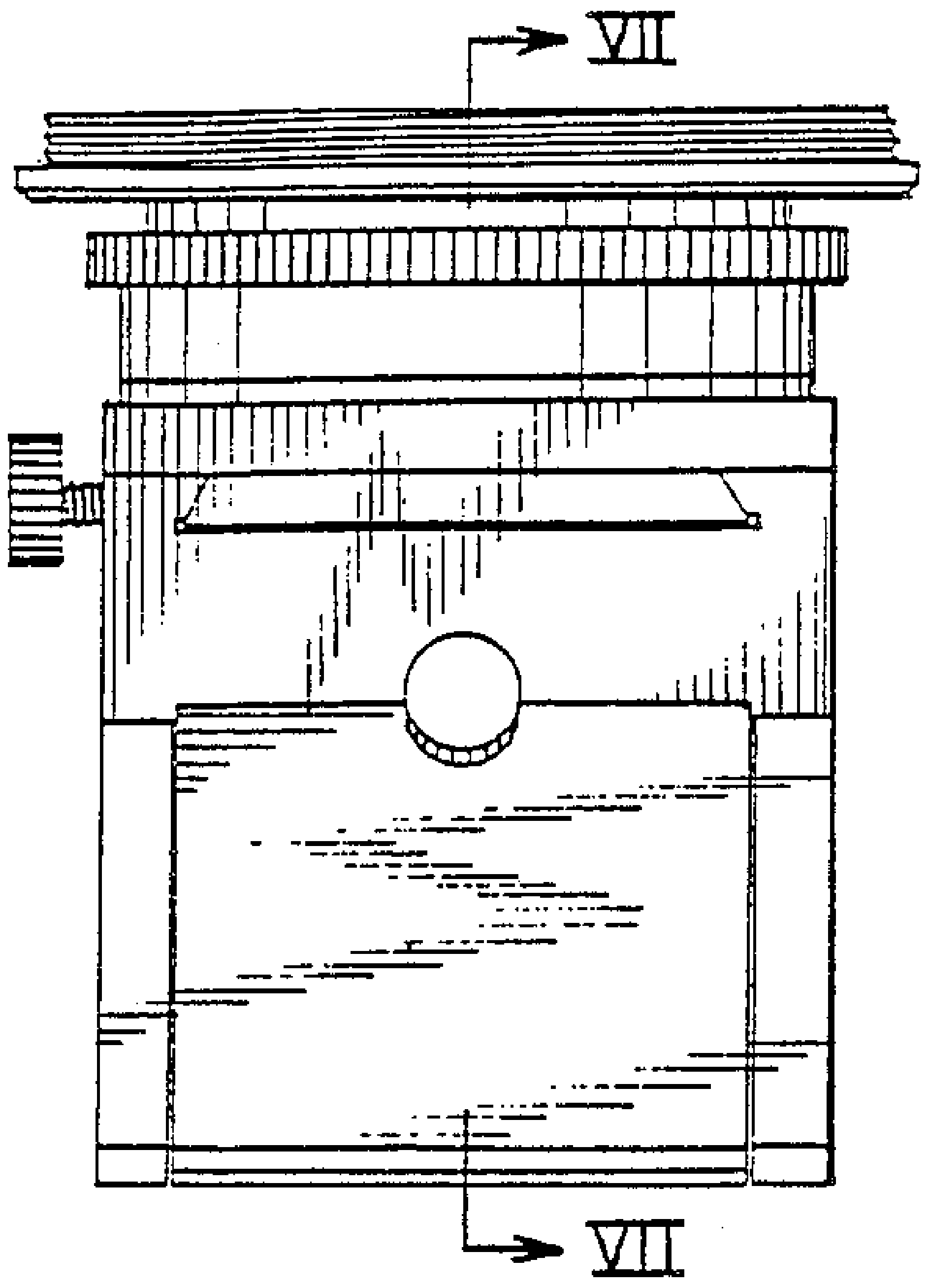


FIG. 1

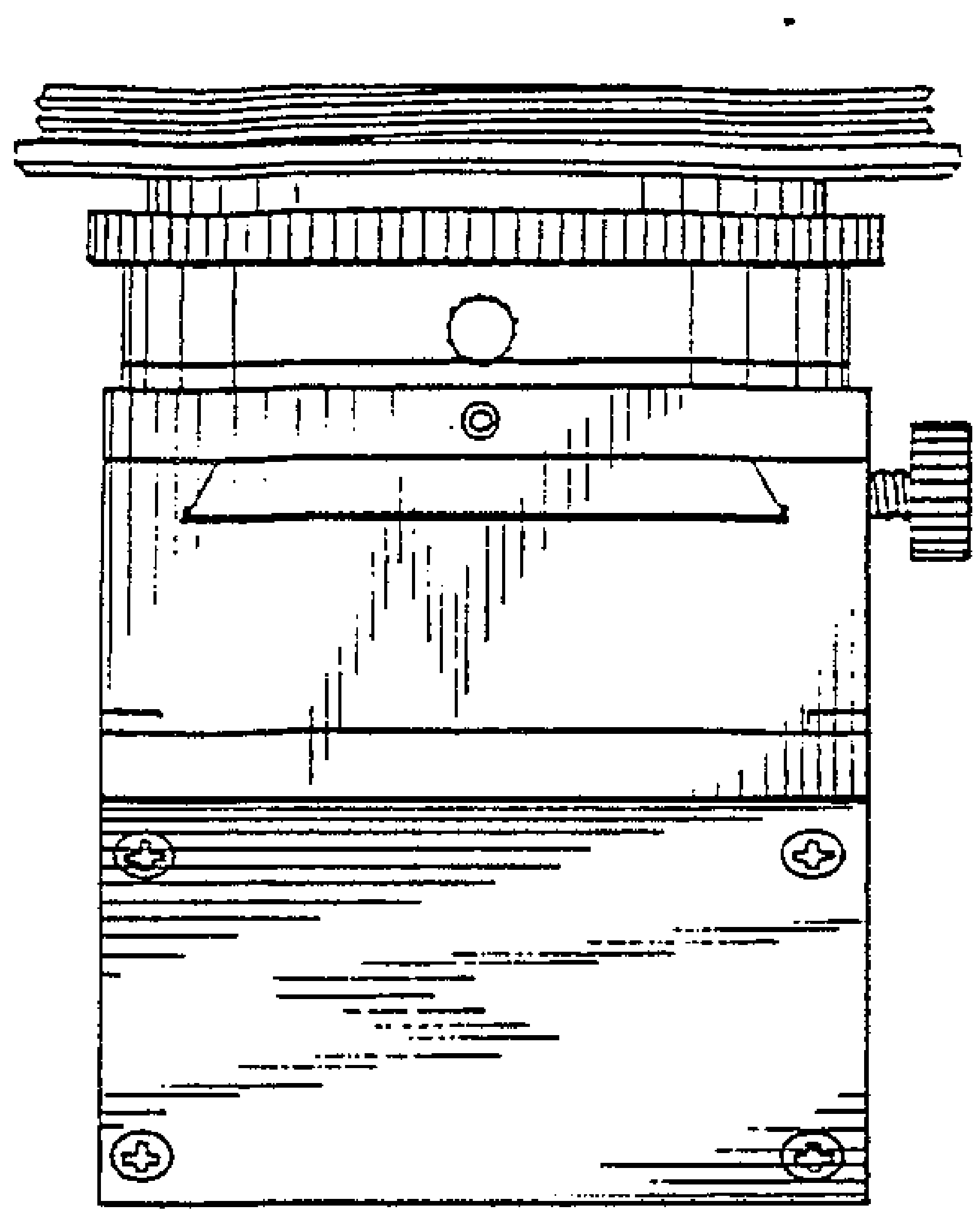


FIG. 2

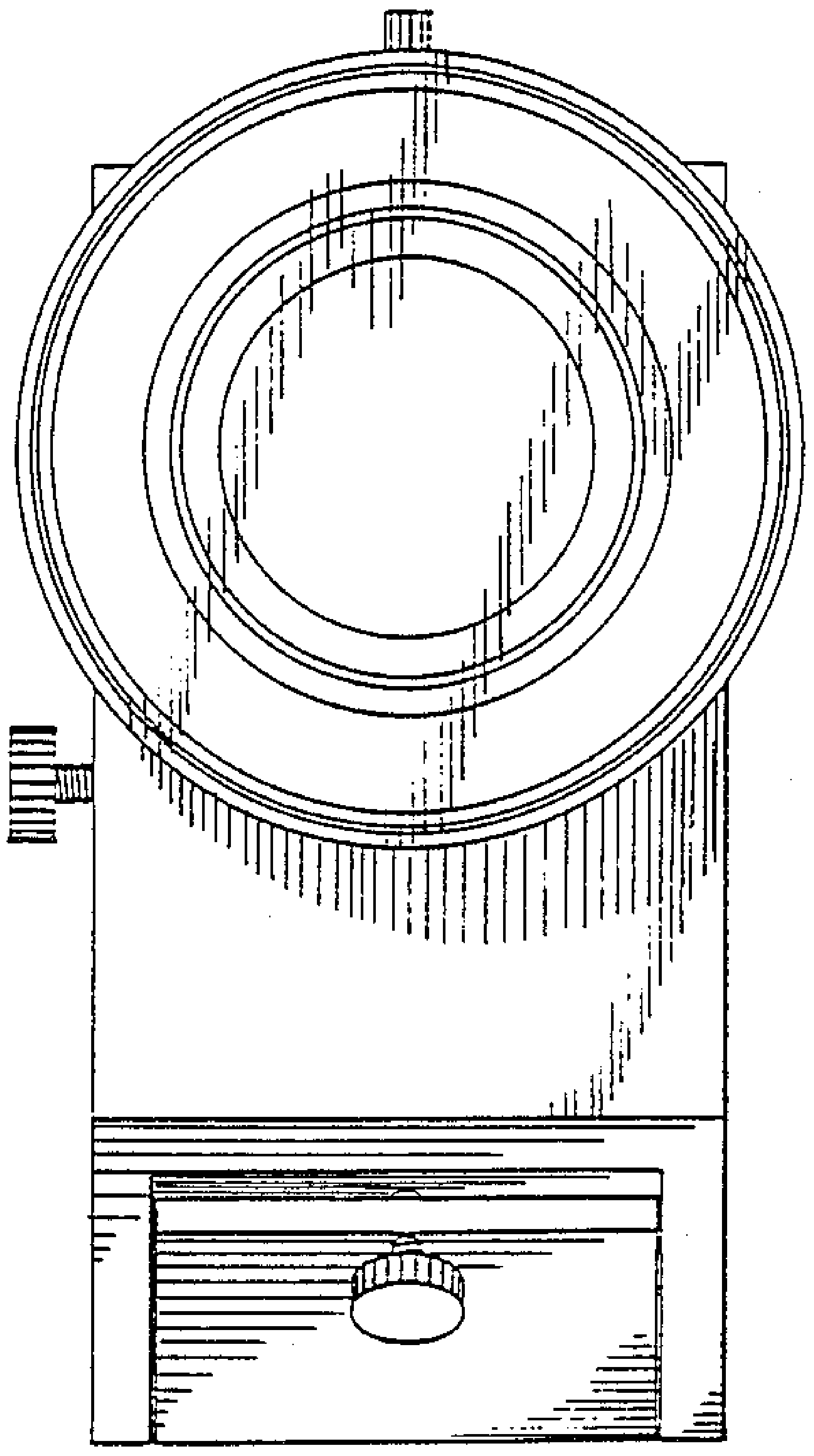


FIG. 3

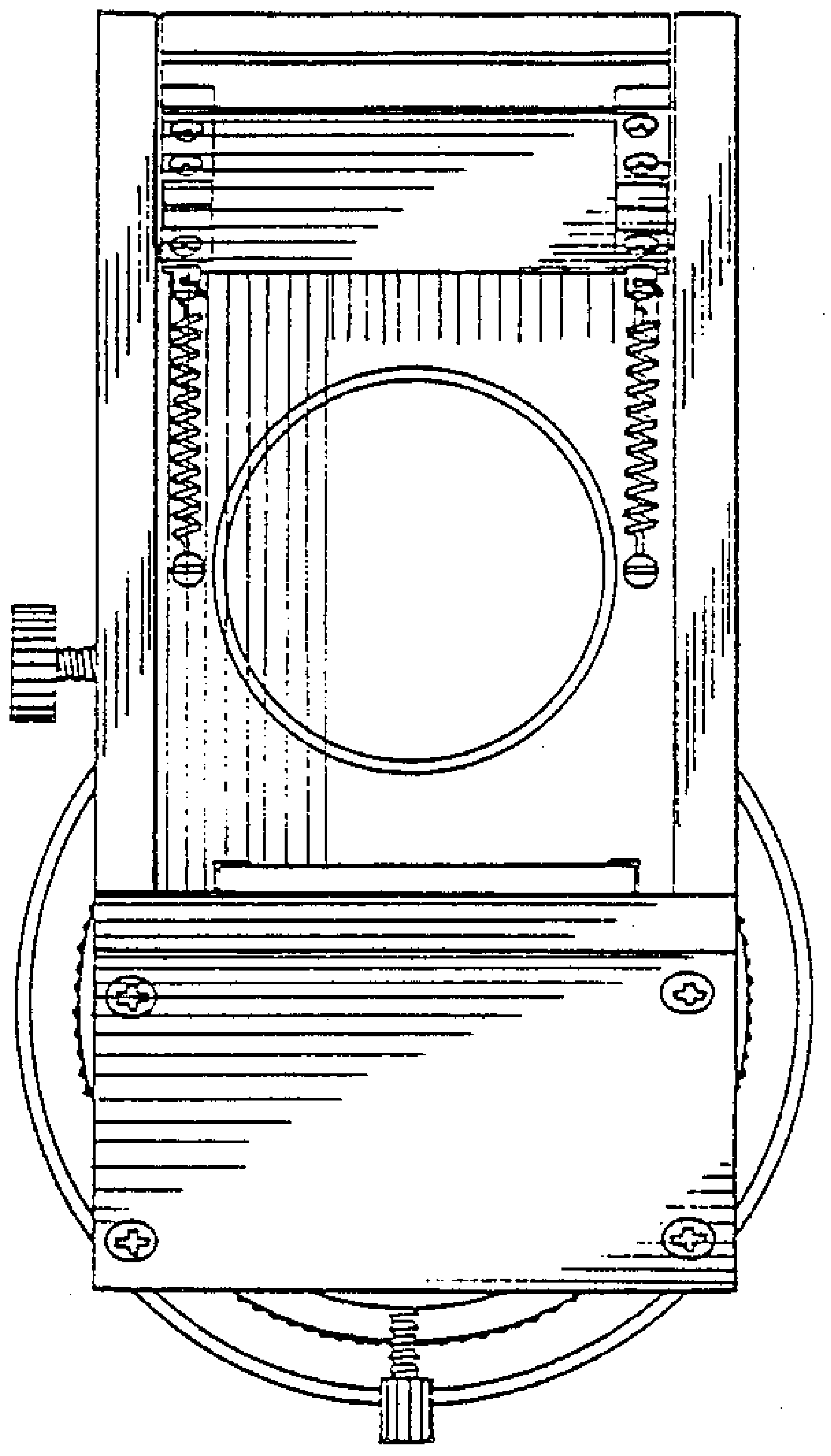


FIG. 4

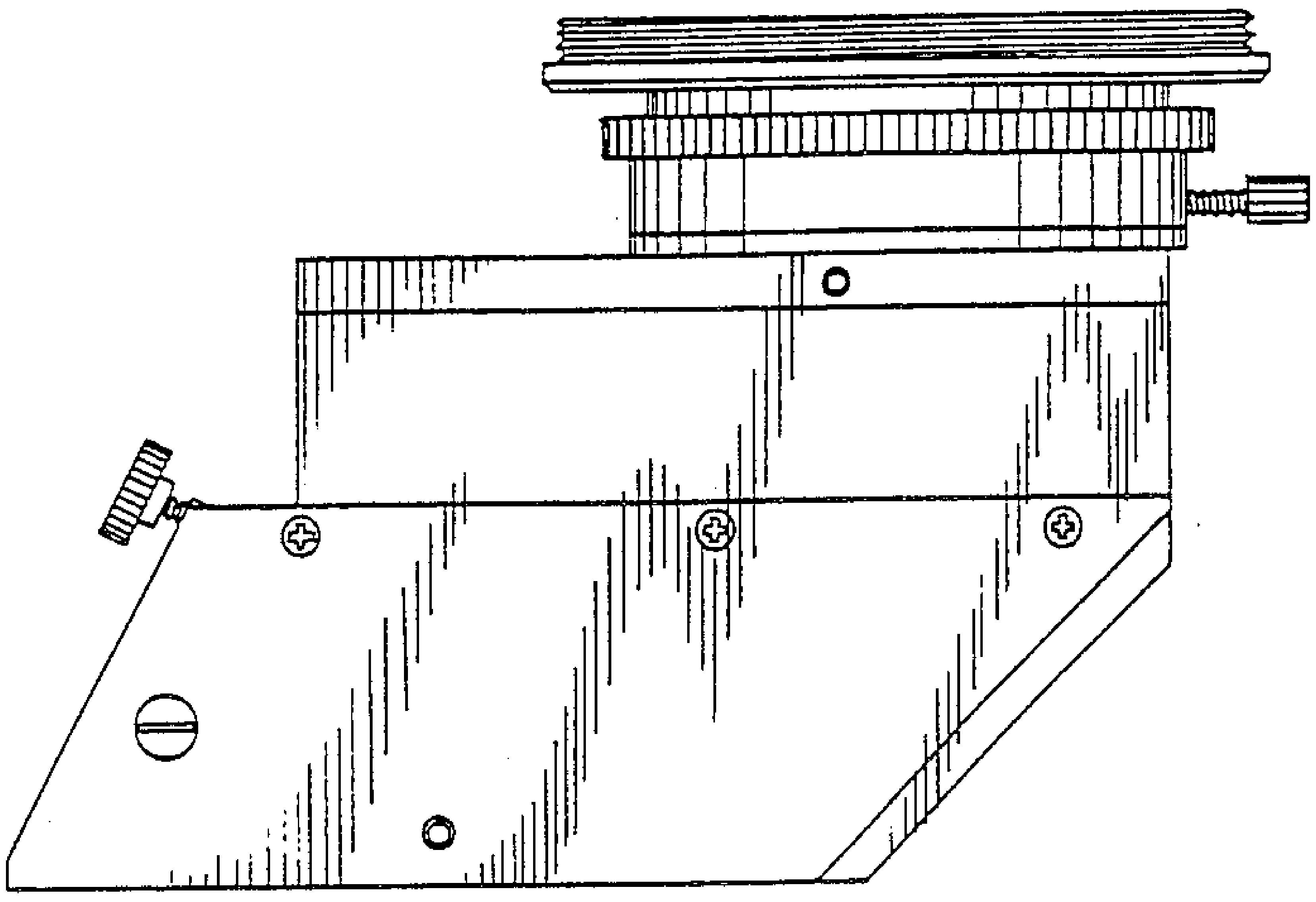


FIG. 6

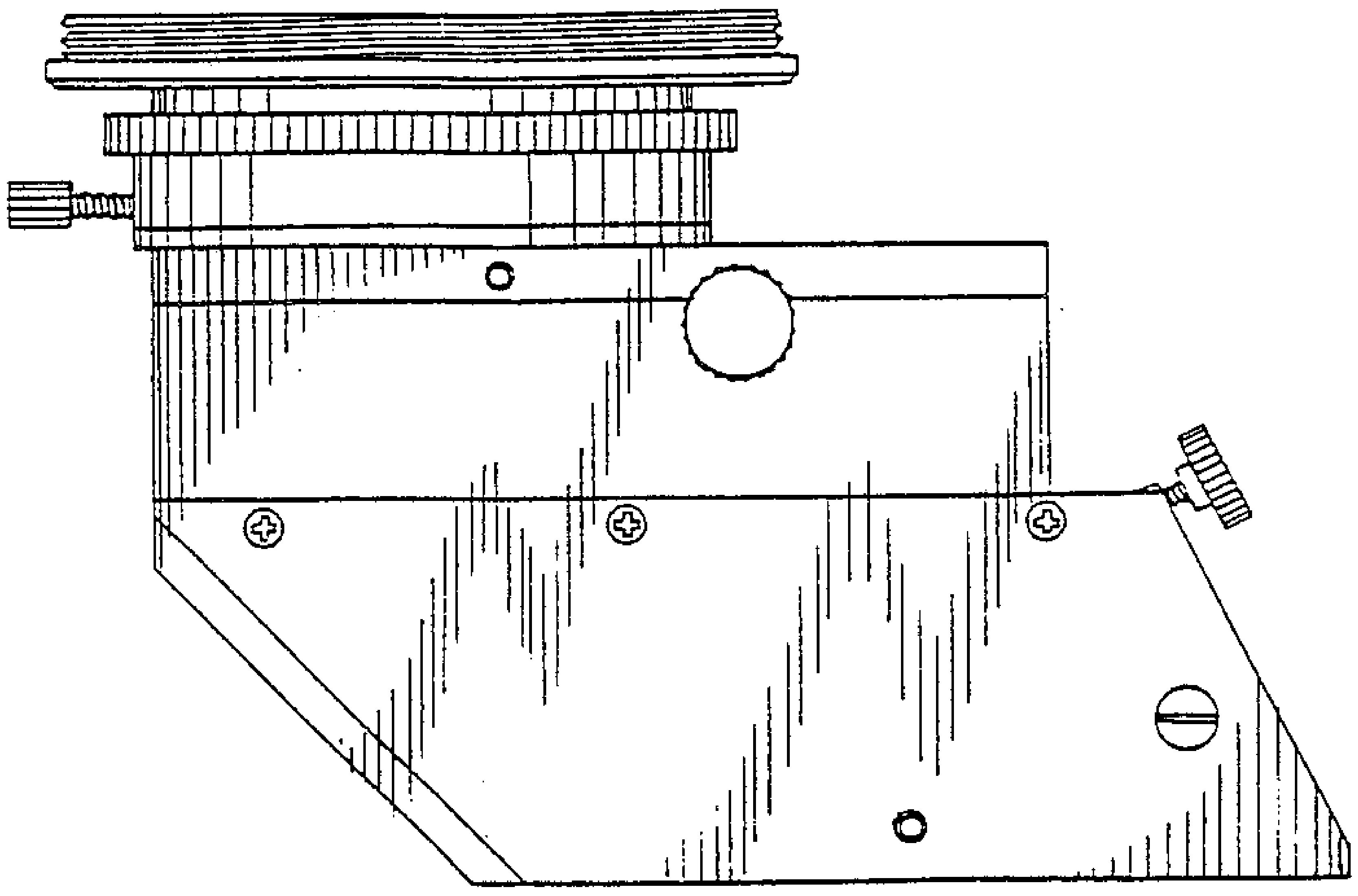


FIG. 5

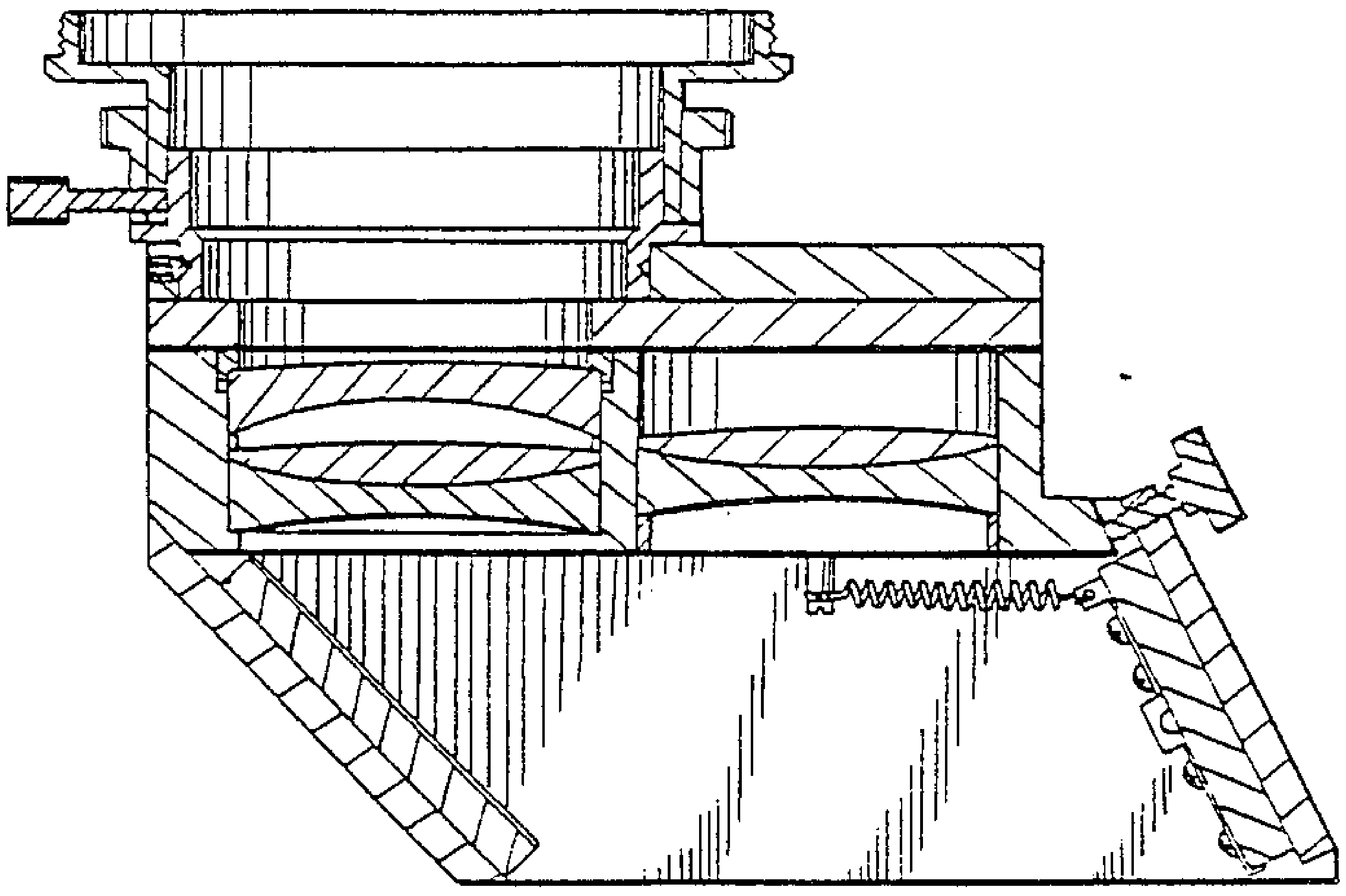


FIG. 7

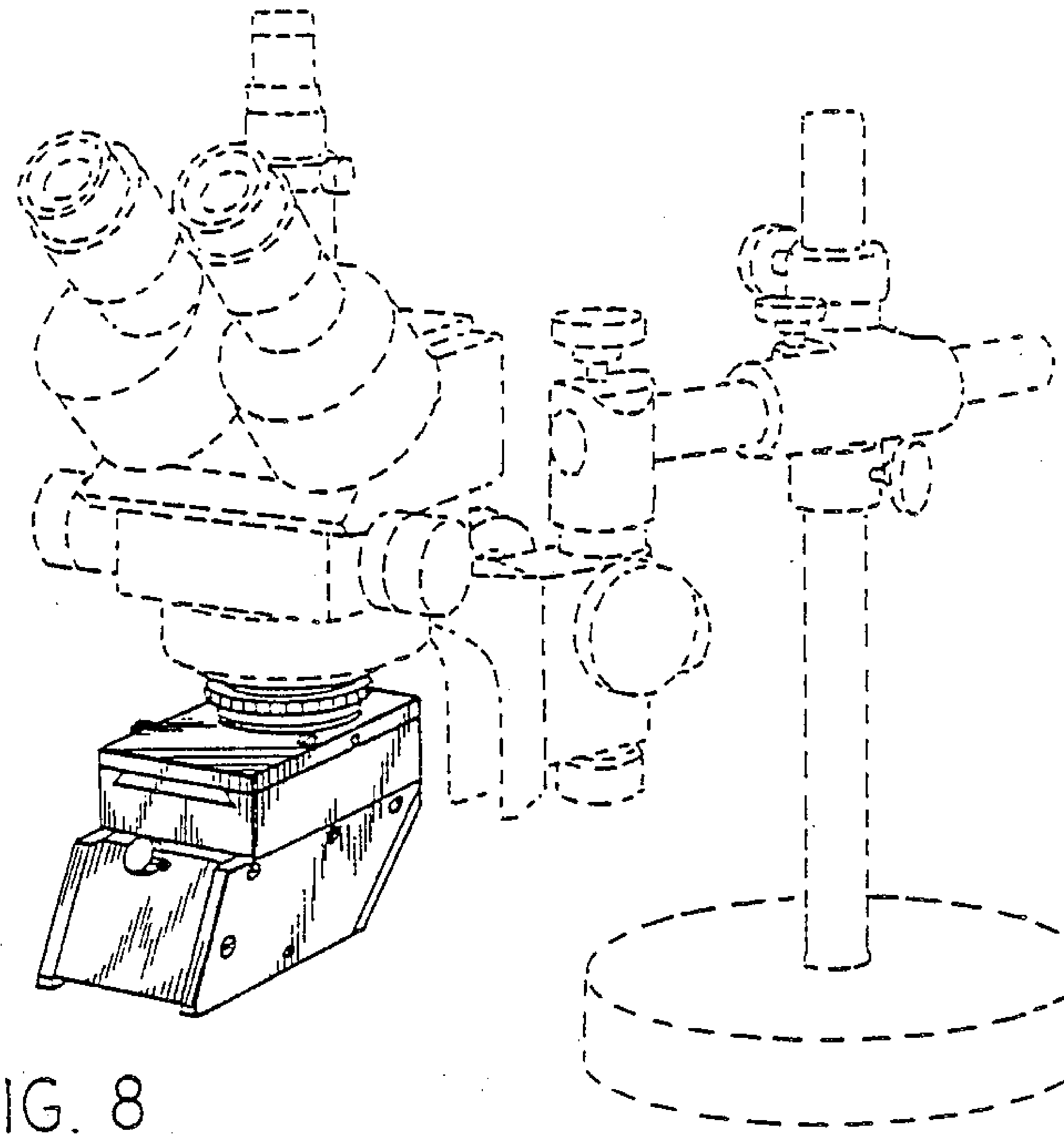


FIG. 8

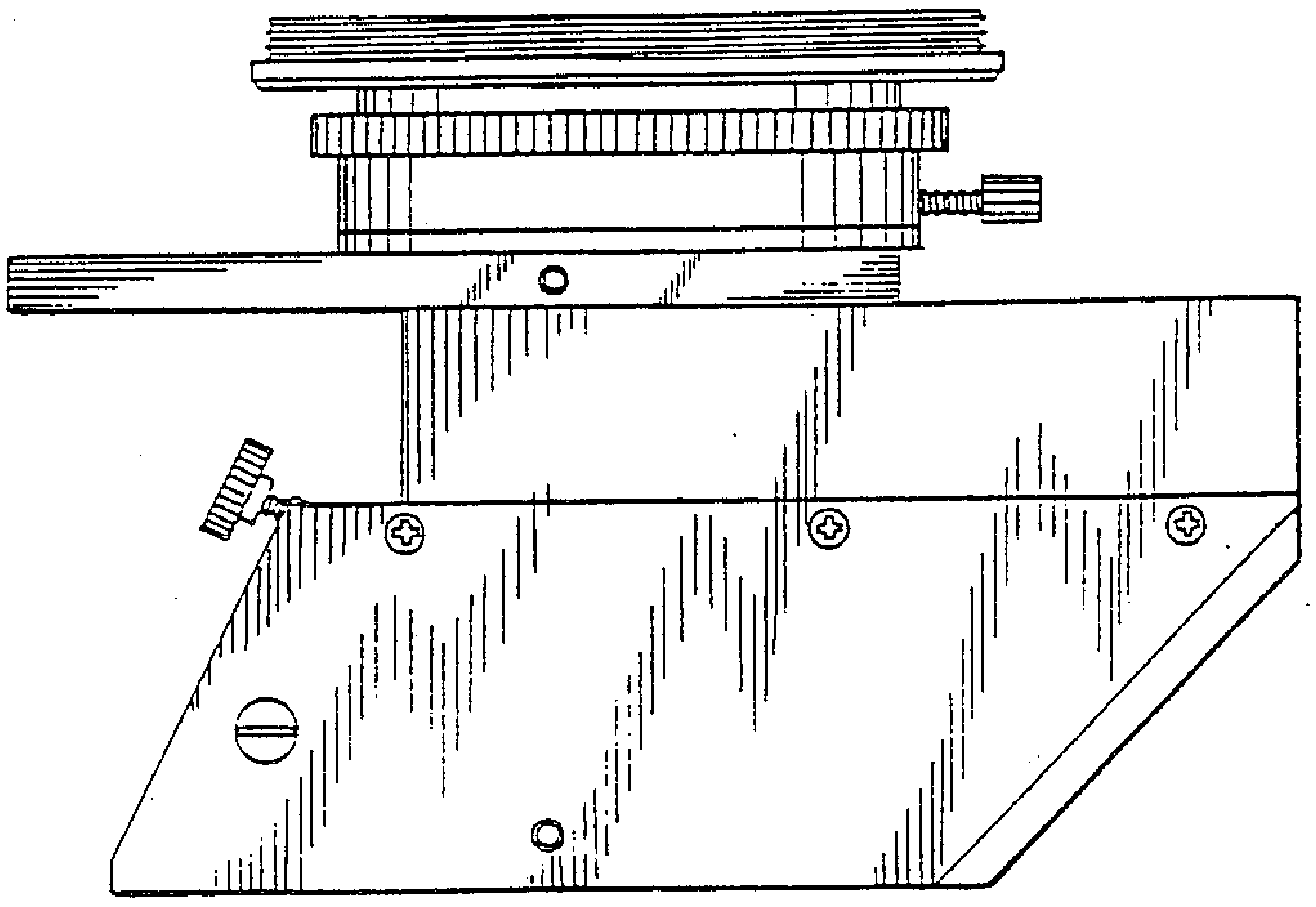


FIG. 9